TOSHIBA Field Effect Transistor Silicon N Channel Junction Type

2SK117

Low Noise Audio Amplifier Applications

Unit: mm

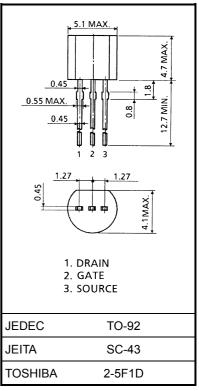
- High $|Y_{fs}|$: $|Y_{fs}| = 15 \text{ mS (typ.) (VDS} = 10 \text{ V, VGS} = 0)$
- High breakdown voltage: $V_{\rm GDS} = -50 \text{ V}$
- Low noise: NF = 1.0dB (typ.)

(VDS = 10 V, ID = 0.5 mA, f = 1 kHz, RG = 1 k Ω)

• High input impedance: $I_{GSS} = -1 \text{ nA (max) (V}_{GS} = -30 \text{ V)}$

Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Gate-drain voltage	V_{GDS}	-50	V
Gate current	IG	10	mA
Drain power dissipation	P _D	300	mW
Junction temperature	Tj	125	°C
Storage temperature range	T _{stg}	-55~125	°C



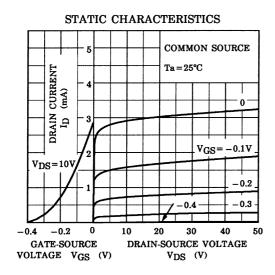
Weight: 0.21 g (typ.)

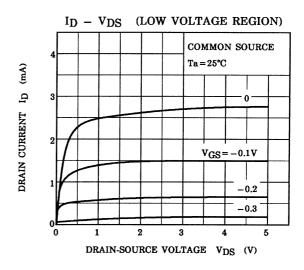
Electrical Characteristics (Ta = 25°C)

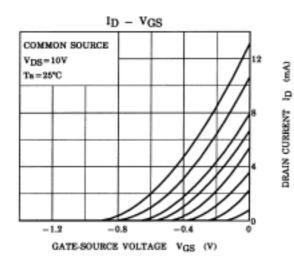
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate cut-off current	I _{GSS}	$V_{GS} = -30 \text{ V}, V_{DS} = 0$	_	_	-1.0	nA
Gate-drain breakdown voltage	V (BR) GDS	$V_{DS} = 0$, $I_G = -100 \mu A$	-50	_	_	V
Drain current	I _{DSS} (Note)	V _{DS} = 10 V, V _{GS} = 0	1.2	_	14	mA
Gate-source cut-off voltage	V _{GS (OFF)}	$V_{DS} = 10 \text{ V}, I_D = 0.1 \mu A$	-0.2	_	-1.5	V
Forward transfer admittance	Y _{fs}	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ kHz}$	4.0	15	_	mS
Input capacitance	C _{iss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	13	_	pF
Reverse transfer capacitance	C _{rss}	$V_{GD} = -10 \text{ V}, I_D = 0, f = 1 \text{ MHz}$	_	3	_	pF
Noise figure	NF (1)	V_{DS} = 10 V, R_G = 1 k Ω I_D = 0.5 mA, f = 10 Hz	_	5	10	dB
	NF (2)	$V_{DS} = 10 \text{ V}, R_G = 1 \text{ k}\Omega$ $I_D = 0.5 \text{ mA}, f = 1 \text{ kHz}$		1	2	uB

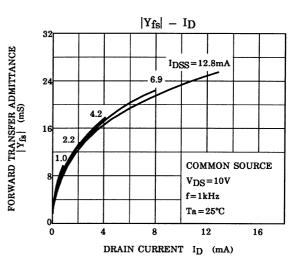
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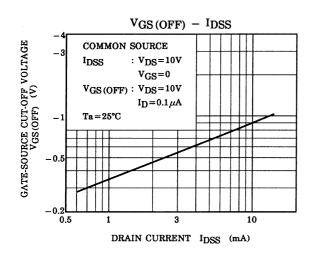
Note: IDSS classification Y: 1.2~3.0 mA, GR: 2.6~6.5 mA, BL: 6~14 mA

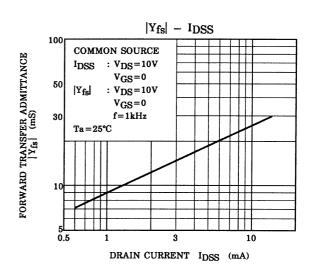




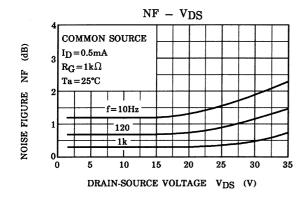


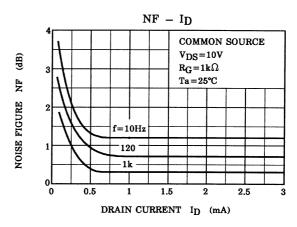


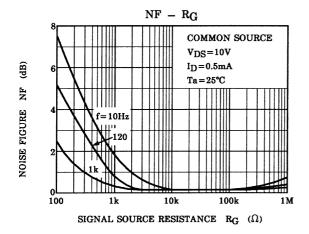


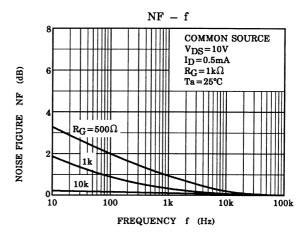


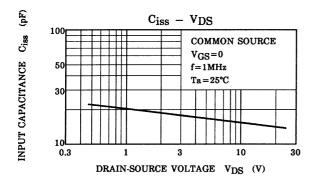
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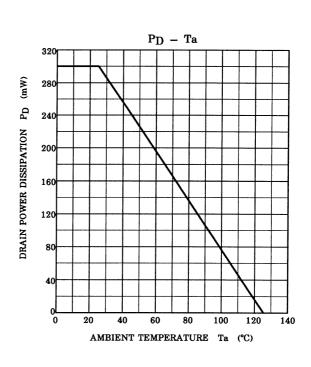


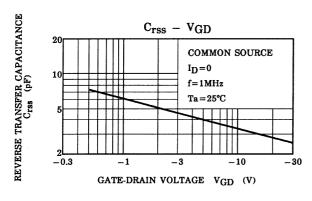












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